


<b>Search Notes</b>  	<b>Application/Control No.</b>  10607780	<b>Applicant(s)/Patent Under Reexamination</b>  PRATLEY ET AL.
	<b>Examiner</b>  LE NGUYEN	<b>Art Unit</b>  2174

SEARCHED			
Class	Subclass	Date	Examiner
715	751	1/29/08	lvn

SEARCH NOTES		
Search Notes	Date	Examiner
EPO, JPO; ACM library, IEEE Xplore; PGPub, USPAT: 715/751	1/29/08	lvn

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
715	751	1/29/08	lvn